

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10586046	KIMMEL, RON
	<b>Examiner</b>	<b>Art Unit</b>
	SHEELA C CHAWAN	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	154, 286, 293, 268, 151, 199, 141, 203, 206, 207, 210, 291, 149,	7/19/09	SCC
356	376, 374, 375, 4.09, 610, 608	"	"
250	559.36, 236, 208.1, 205, 201.6, 237G, 559.38	"	"
359	17,	"	"
382	154	2/25/10	SCC
250	236, 559.38	2/25/10	SCC
359	17	2/25/10	SCC
356	608	2/25/10	SCC
SEARCH UP-DATE		2/25/10	SCC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	7/19/09	SCC
INVENTOR NAME SEARCH	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	2/25/10	SCC
250/559.36,236,208.1,205,201.6,237G,559.38,201.4.CCLS.	2/25/10	SCC
356/608,4.01,243.1,3.03,4.07.CCLS.	2/25/10	SCC
359/17,.CCLS.; 382/\$.CCLS.	2/25/10	SCC
INTERFERENCE SEARCH	2/25/10	SCC
SEARCH IEEE OR INSPEC DATA BASE,	2/25/10	SCC
SEARCH UP-DATE	2/25/10	SCC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	154	2/25/10	SCC
250	236, 559.38	2/25/10	SCC
359	17	2/25/10	SCC
356	608	2/25/10	SCC

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